Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/830,049	OHNISHI ET AL.	
Examiner	Art Unit	
Linh V. Nguyen	2819	

SEARCHED					
Class	Subclass	Date	Examiner		
330	286,295 277,59 176,277	3/8/2007	LN		
330	301-311	3/8/2007	LN		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
1	ct searched - rintout	3/8/2007	LN	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See East searched printout	3/8/2007	LN		